

<b>Notice of References Cited</b>	Application/Control No. 10/717,521	Applicant(s)/Patent Under Reexamination HO ET AL.	
	Examiner Feben M. Haile	Art Unit 2616	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0083284 A1	04-2004	Ofek et al.	709/224
*	B	US-7,197,660 B1	03-2007	Liu et al.	714/4
*	C	US-6,954,436 B1	10-2005	Yip et al.	370/254
*	D	US-2005/0265346	12-2005	Ho et al.	370/392
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
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**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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**NON-PATENT DOCUMENTS**

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